



- To Advance Wafer Test Technology
- To Serve and Inform the Wafer Test Professional
- To Boldly Go Where No Workshop Has Gone Before

Long Beach, CA, June 9 to 12, 2002



NEW LOCATION THIS YEAR





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WHAT IS SWTW - 2002?

- **“THE” Conference for wafer test professionals**
- **Not a theoretical or academic conference**
- **Provides practical solutions to real problems**
- **Mixture of vendor and user presentations**
- **Open discussions and networking**
- **Informal and relaxed atmosphere**



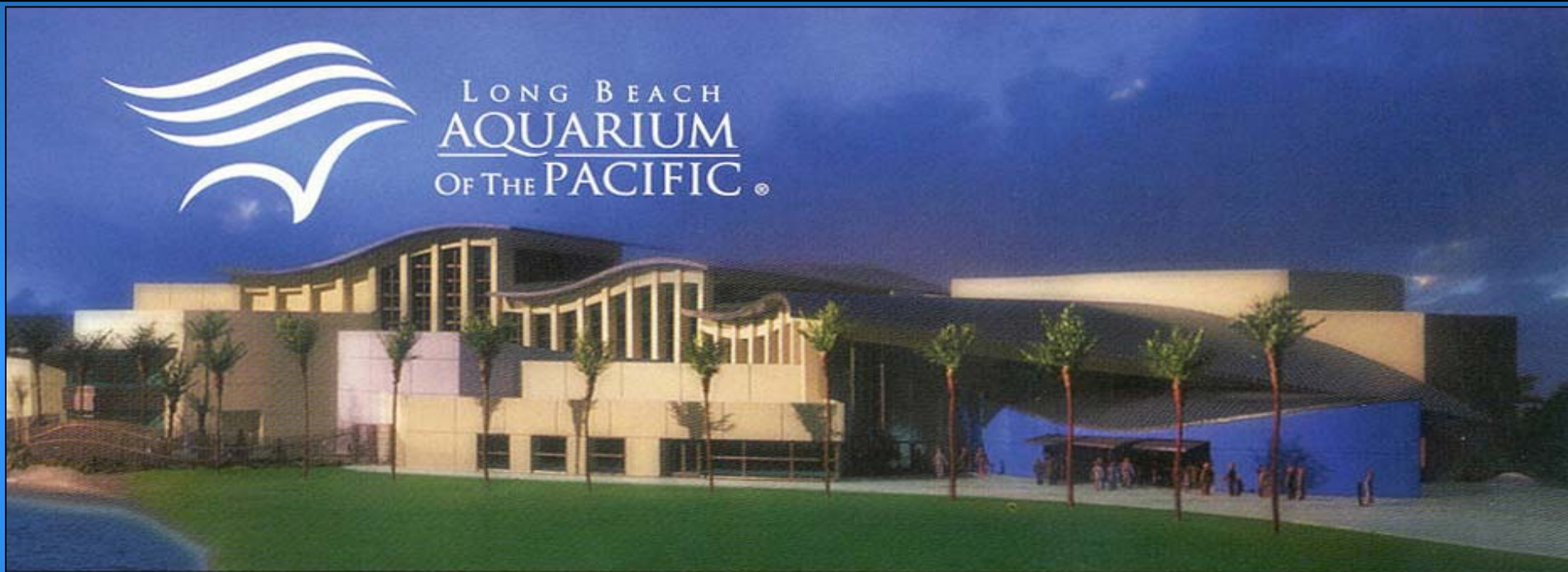
INFORMAL CONFERENCE

- Long breaks for discussions
- Plenty of networking opportunities
- Numerous social gatherings
- Recreational activities
- Meet new people & *have some fun!*

(Don't tell the IEEE about the fun part)



RECREATIONAL ACTIVITIES





TECHNICAL PROGRAM

- **Sunday, June 9, 2002**
 - ◆ **Wafer Level Burn-In Tutorial**
 - ◆ **Keynote Speaker, Charles Lassen, Prismark Partners**

- **Monday, June 10, 2002**
 - ◆ **High Power Probing**
 - ◆ **Process Optimization**
 - ◆ **Advances in Probe Card Analyzers**
 - ◆ **Probe Potpourri**
 - ◆ **Cocktail Reception & Team Techno Trivia Contest**
 - ◆ **Invited Dinner Speaker, Steven Strauss, Intel**



TECHNICAL PROGRAM

- **Tuesday, June 11, 2002**
 - ◆ C4 Bump Challenges
 - ◆ RF and Parametric Probe
 - ◆ Afternoon Social Activities, Pacific Aquarium
 - ◆ Cocktail Reception and After Dinner Presentation
 - ◆ Cassini Spacecraft Exploration of Saturn
- **Wednesday June 12, 2002**
 - ◆ What's Next for Probers?
 - ◆ New Probe Technologies
 - ◆ Awards Luncheon



RECOGNITION & AWARDS

- **Best Overall Presentation**
- **Best Data Presented**
- **Best Presentation, Tutorial in Nature**
- **Most “Inspirational” Presentation**
- **Team Techno Trivia Winners**
- **Other “Special Awards”**



The BEST from SWTW - 2001

- Ted Khoury, Robert Aldaz, Dr. David Yu, and Gert Hohenwarter, Adventest America
“Silicon Finger Technology and the Photo-Finger Technology for High-Performance Probe”
- Roger Sinsheimer, Xandex, Inc., and Ken Karklin, Agilent Technologies
“Enabling X144 Flash Memory Test”
- Gobinda Das, Ph.D., Fredrick Taber, IBM Microelectronics
“A High Performance C4 Probe: TFI”



<http://www.swtest.org>

- **Central Online Repository**
 - ◆ **Past presentations**
 - ◆ **Online registration**
 - ◆ **With more features to come.....**
- **Tremendous continued success!!**
 - ◆ **Over eight thousand visits to the site last year**
 - ◆ **Thanks to “web-efforts” of Jerry Broz
and Rey Rincon**



Test Technology Periodicals

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EE - Evaluation Engineering
Nelson Publishing
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Final Test Report
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IEEE Journals and Transactions
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We think of everything, almost...

Souvenirs and a “Post Card Home”

***“You get to go to Long Beach
and have a lot of fun.....***

..... and all I get is this

crummy toy!”